

**Notice of References Cited**

Application/Control No.

10/044,502

Applicant(s)/Patent Under  
Reexamination  
SCHERER, AXEL

Examiner

Hung T Vy

Art Unit

2828

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,955,749	09-1999	Joannopoulos et al.	257/98
	B	US-5,568,574	10-1996	Tanguay et al.	385/14
	C	US-4,503,447	03-1985	Iafrate et al.	257/15
	D	US-6,058,127	05-2000	Joannopoulos et al.	372/92
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	O. Painter et al.; Two-Dimensional Photonic band-Gap Defect Mode Laser ; June 1999; Science Vol. 284 ; p 1819.
	V	W. d. Zhou et la.;Electrically Injected Single-Defect photonic bandgap Surface-Emitting Laser at room Temperature; August 2000; electronics Letter ; Vol. 36; No. 18.
	W	S. Y. Lin et al.; Dirrect Measurement of the Quality Factor In Two-demensional Photonic-Crystal Mirocavity; December 2001; Optical Society of America Vol.26, No. 23; p. 1903.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.